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## THE UNITED STATES PATENT AND TRADEMARK OFFICE

## In re Application of:

Robert Benware

Serial No.:

10/602,357

Group Art Un

2857

Filed:

June 23, 2003

Examiner:

Raymond, Edward

For:

Method of Screening Defects Using

Low Voltage IDDQ Measurement

Atty Docket:

81563 / 02-6301

Thereby certify that this correspondence is being deposited with the U.S. Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P. O. Box 1450, Alexandria, VA 22313-1450,

on the date below:

Connie Del Castillo

01/06/1

Signature

## **CERTIFICATION UNDER 37 C.F.R. 3.73(b)**

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

Sir:

LSI Logic Coporation, a Delaware corporation, certifies that it is the assignee of the entire right, title and interest in the patent application.

The undersigned has reviewed all the documents in the chain of title of the patent application identified above and, to the best of the undersigned's knowledge and belief, title is in the assignee identified above.

The undersigned (whose title is supplied below) is empowered to act on behalf of the assignee.

I hereby declare that all statements made herein of my own knowledge are true, and that all statements made on information and belief are believed to be true; and further, that these statements are made with the knowledge that willful false statements, and the like so made, are punishable by fine or imprisonment, or both, inder Section 1001, Title 18 of the United States Code, and that such willful false statements may jeopardize the validity of the application or any patent issuing thereon.

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Date: //S

Respectfully submitted,

Sandeep Jaggi Chief IP Counsel

Corporate Assistant Secretary
LSI LOGIC CORPORATION